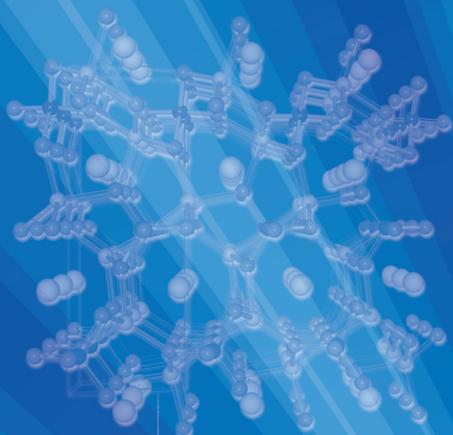
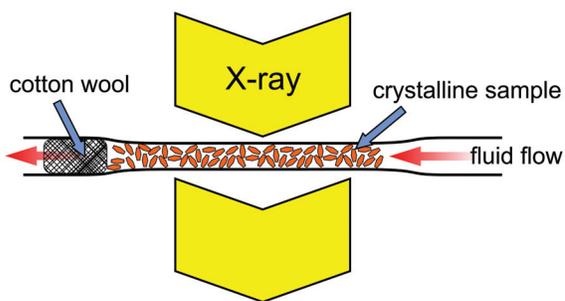


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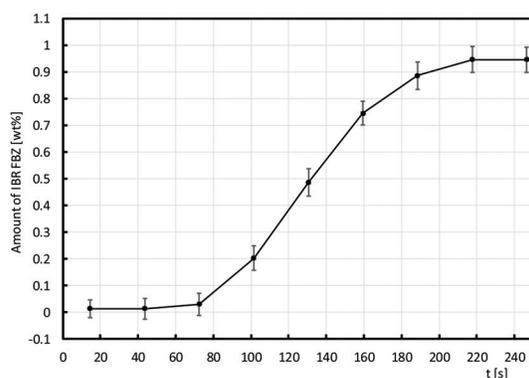
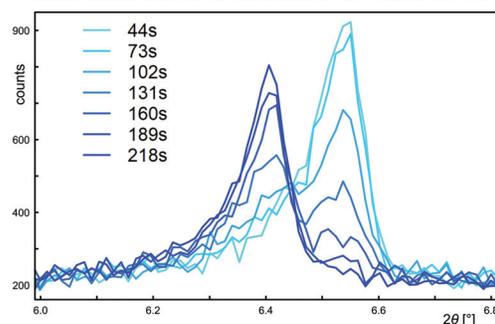
Journal of Materials Characterization



Flow-through capillary system for PXRD



Reaction of IBR FBZ solvate with oversaturated solution of ibuprofen in fluorobenzene a function of flow time



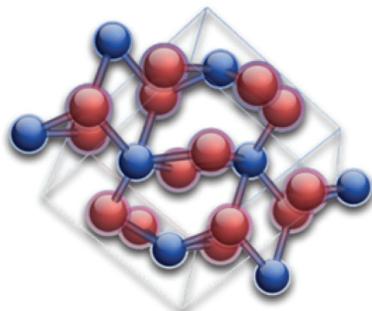
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Powder Diffraction

An International Journal of Materials Characterization

Editor-in-Chief

Camden Hubbard
Applied Diffraction Services, U.S.A.
camden.hubbard@me.com

Managing Editor

Nicole M. Ernst Boris
International Centre for Diffraction Data, U.S.A.
boris@icdd.com

Production Editor

Kayla Riddleberger
Cambridge University Press, U.S.A.
kriddleberger@cambridge.org

Editors for New Diffraction Data

Soorya Kabekkodu
International Centre for Diffraction Data, U.S.A.
kabekkodu@icdd.com

Stacy Gates-Rector
International Centre for Diffraction Data, U.S.A.
gates-rector@icdd.com

Associate Editor for New Diffraction Data

Frank J. Rotella
Argonne National Laboratory (Retired), U.S.A.
fjrotella1949@gmail.com

Editors

Xiaolong Chen
Institute of Physics, Chinese Academy of Sciences, China
xlchen@iphy.ac.cn

José Miguel Delgado
Universidad de Los Andes, Venezuela
miguel@ula.ve

Norberto Masciocchi
Università dell'Insubria, Italy
norberto.masciocchi@uninsubria.it

Editors for Crystallography Education

James Kaduk
Poly Crystallography Inc., U.S.A.
Kaduk@polycrystallography.com

Brian H. Toby
Argonne National Laboratory, U.S.A.
brian.toby@anl.gov

International Reports Editor

Winnie Wong-Ng
National Institute of Standards and Technology, U.S.A.
winnie.wong-ng@nist.gov

Calendar of Meetings and Workshops Editor

Gang Wang
Institute of Physics, Chinese Academy of Sciences, China
gangwang@iphy.ac.cn

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On the Cover: The manuscript in this issue titled "Testing the flow-through capillary for the study of re-solvation processes in pharmaceutical compounds" by J. Rohlicek, V. Zvonicek, E. Skorepova, and M. Soos describes development and testing of a flow-through capillary sample holder that enables in-situ PXRD studies of re-solvation processes. Irradiated length is ~20 mm. A 1-D XRD detector sampled a small 2-theta region while a solution was passed thru the capillary. The study showed the in-situ, time dependent changes of the pharmaceutical ibuprofen solvated with anisole or fluorobenzene.

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Powder Diffraction (ISSN: 0885-7156) is published quarterly (4X annually) by the JCPDS-International Centre for Diffraction Data through Cambridge University Press, One Liberty Plaza, 20th floor, New York, NY 10006. Periodicals postage rate paid at New York, NY, and at additional mailing offices. POSTMASTER: Send address changes in the USA, Canada, and Mexico to: Powder Diffraction, Cambridge University Press, Journals Fulfillment Department, One Liberty Plaza, 20th floor, New York, NY 10006. Send address changes elsewhere to Powder Diffraction, Cambridge University Press, Journals Fulfillment Department, UPH, Shaftesbury Road, Cambridge CB2 8BS, England.

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